

Notice of References Cited	Application/Control No. 09/929,995	Applicant(s)/Patent Under Reexamination TERNULLO ET AL.	
	Examiner Sargon N. Nano	Art Unit 2157	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,647,269	11-2003	Hendrey et al.	455/456.3
	B	US-6,738,951	05-2004	Weiss et al.	715/523
	C	US-6,857,013	02-2005	Ramberg et al.	709/223
	D	US-6,505,046	01-2003	Baker, Steven F.	455/456.3
	E	US-6,397,057	05-2002	Malackowski et al.	455/414.1
	F	US-6,381,465	04-2002	Chern et al.	455/466
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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